

Substitute Form PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark OfficeAttorney's Docket No.
09712-333001Application No.
10/659,103**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

(37 CFR § 1.98(b))

Applicant
Henry A. HillFiling Date
September 9, 2003Group Art Unit
1656**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
SAT	AA	US 2003/009067 5	05/15/03	Fujiwara			
↑	AB	US 2002/008967 1	07/11/02	Hill			
	AC	US 2001/003595 9	11/01/01	Hill			
	AD	6,330,105	12/11/01	Rozelle et al.			
	AE	6,304,318	10/16/01	Matsumoto			
	AF	6,252,668	06/26/01	Hill			
	AG	6,246,481	06/12/01	Hill			
	AH	6,236,507	05/22/01	Hill et al.			
	AI	6,181,420	01/30/01	Badami et al.			
	AJ	6,159,644	12/12/00	Hidetoshi			
	AK	6,134,007	10/17/00	Naraki et al.			
	AL	6,046,792	04/04/00	Van Der Werf et al.			
	AM	6,040,096	03/21/00	Kakizaki			
	AN	6,020,964	02/01/00	Loopstra et al.			
	AO	6,008,902	12/28/99	Rinn			
	AP	5,801,832	09/01/98	Van Der Brink			
	AQ	5,781,277	07/14/98	Iwamoto			
	AR	5,757,489	05/26/98	Kawakami			
	AS	5,757,160	05/26/98	Kreuzer			
	AT	5,764,361	06/09/98	Kato et al.			
	AU	5,724,136	03/03/98	Zanoni			
	AV	5,663,893	09/02/97	Wampler et al.			
	AW	5,663,793	09/02/97	de Groot			
↓	AX	5,491,550	02/13/96	Dabbs			
SAT	AY	5,408,318	04/18/95	Slater			

Examiner Signature

S.A. Taven

Date Considered

12-7-05

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
SAT	AZ	5,187,543	02/16/93	Ebert			
↑	AAA	5,151,749	09/29/92	Tanimoto et al.			
	ABB	5,114,234	05/19/92	Otsuka et al.			
	ACC	5,064,289	11/12/91	Bockman			
	ADD	4,881,816	11/21/89	Zanoni			
	AEE	4,859,066	08/22/89	Sommargren			
	AFF	4,802,765	02/07/89	Young et al.			
	AGG	4,790,651	12/13/88	Brown et al.			
	AHH	4,711,573	12/08/87	Wijntjes et al.			
	AII	4,662,750	05/07/87	Barger			
SAT	AJJ	4,606,638	08/19/86	Sommargren			

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
SAT	AKK	WO 01/90686	11/29/01	WIPO				
SAT	ALL	JP 10-260009 Translation of Abstract Only	09/29/98	Japan			X	
SAT	AMM	JP 7-351078	12/25/95	Japan				
SAT	ANN	JP 8-117083 Abstract Only	04/15/96	Japan			X	
—	AOO	JP 9-178415 Translation of Abstract Only	07/11/97	Japan			X	
—	APP	JP 9-280822 Translation of Abstract Only	10/31/97	Japan			X	

From
10/360,361

Other Documents (include Author, Title, Date, and Place of Publication)

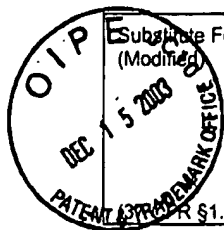
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SAT	AQQ	Bennett, S.J. . "A Double-Passed Michelson Interferometer." Optics Communications, 4:6, pp. 428-430, 1972.
SAT	ARR	Wu et al. "Analytical modeling of the periodic nonlinearity in heterodyne interferometry." Applied Optics, 37:28, pp. 6696-6700, 1998.
SAT	ASS	Hines et al. "Sub-Nonometer Laser Metrology - Some Techniques and Models. ESO Conference on High-Resolution Imaging by Interferometry II, pp.1195-1204, 1991
SAT	ATT	Bobroff, Norman. "Recent advances in displacement measuring interferometry." Meas. Sci. Technol. 4, pp. 907-926, 1993.
SAT	AUU	Oka et al. "Polarization heterodyne interferometry using another local oscillator beam." Optics Communications, 92, pp. 1-5, 1992.
SAT	AVV	Badami et al. "Investigation of NonLinearity in High Accuracy Heterodyne Laser Interferometry." American Society for Precision Engineering, 1997 Proceedings, 16, pp. 153-156, 1997.
SAT	AWW	Bobroff, Norman. "Residual errors in laser interferometry from air turbulence and nonlinearity." Applied Optics, 26:13, pp. 2676-2686, 1987.

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U.S. Patent Documents

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SAT	AA	5,363,196	11/08/1994	Cameron	356	358	
SAT	AB	5,790,253	08/04/1998	Kamiya	356	363	
SAT	AC	6,137,574	10/24/2000	Hill	356	351	
	AD						
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	AG						
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	AJ						
	AK						

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	AL							
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	AO							
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	AS	
	AT	

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